

<b>Notice of References Cited</b>	Application/Control No. 10/084,182	Applicant(s)/Patent Under Reexamination NAKANISHI ET AL.	
	Examiner Sin J. Lee	Art Unit 1752	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0086233	07-2002	KAWAUCHI et al.	430/270.1
*	C	US-4,671,854	06-1987	Ishikawa et al.	216/18
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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